

Application/Control No.	Applicant(s)/Patent under Reexamination
10/576,645	STOLTE ET AL.
Examiner	Art Unit
Trinh T. Nauven	3644

	SEARCHED				
Class	Subclass	Date	Examiner		
119	14.01 14.02 14.08 14.14 14.18	1/2/2010	TTN		
	14.13				

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

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